

Notice of References Cited	Application/Control No. 10/661,638	Applicant(s)/Patent Under Reexamination HIRAIWA ET AL.	
	Examiner Lois Zheng	Art Unit 1742	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,656,334	12-2003	Tseng et al.	204/276
	B	US-			
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	D	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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	N	JP2000-160390	06-2000	Japan	Fumio et al.	C25D 7/12
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NON-PATENT DOCUMENTS

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